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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	67MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	62
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3666axi-202t

The switching frequency is set to 400 kHz using an oscillator integrated into the boost converter. The boost converter can be operated in two different modes: active and standby. Active mode is the normal mode of operation where the boost regulator actively generates a regulated output voltage. In standby mode, most boost functions are disabled, thus reducing power consumption of the boost circuit. Only minimal power is provided, typically < 5 µA to power the PSoC device in Sleep mode. The boost typically draws 250 µA in active mode and 25 µA in standby mode. The boost operating modes must be used in conjunction with chip power modes to minimize total power consumption. Table 6-1 lists the boost power modes available in different chip power modes.

Table 6-1. Chip and Boost Power Modes Compatibility

Chip Power Modes	Boost Power Modes
Chip-active or alternate active mode	Boost must be operated in its active mode.
Chip-sleep mode	Boost can be operated in either active or standby mode. In boost standby mode, the chip must wake up periodically for boost active-mode refresh.
Chip-hibernate mode	Boost can be operated in its active mode. However, it is recommended not to use the boost in chip hibernate mode due to the higher current consumption in boost active mode.

6.2.2.1 Boost Firmware Requirements

To ensure boost inrush current is within specification at startup, the **Enable Fast IMO During Startup** value must be unchecked in the PSoC Creator IDE. The **Enable Fast IMO During Startup** option is found in PSoC Creator in the design wide resources (cydwr) file **System** tab. Un-checking this option configures the device to run at 12 MHz vs 48 MHz during startup while configuring the device. The slower clock speed results in reduced current draw through the boost circuit.

6.2.2.2 Boost Design Process

Correct operation of the boost converter requires specific component values determined for each designs unique operating conditions. The C_{BAT} capacitor, Inductor, Schottky diode, and C_{BOOST} capacitor components are required with the values specified in the electrical specifications, Table 11-7 on page 78. The only variable component value is the inductor L_{BOOST} which is primarily sized for correct operation of the boost across operating conditions and secondarily for efficiency. Additional operating region constraints exist for V_{OUT}, V_{BAT}, I_{OUT}, and T_A.

The following steps must be followed to determine boost converter operating parameters and L_{BOOST} value.

1. Choose desired V_{BAT}, V_{OUT}, T_A, and I_{OUT} operating condition ranges for the application.
2. Determine if V_{BAT} and V_{OUT} ranges fit the boost operating range based on the **T_A range over V_{BAT} and V_{OUT}** chart, Figure 11-8 on page 78. If the operating ranges are not met, modify the operating conditions or use an external boost regulator.
3. Determine if the desired ambient temperature (T_A) range fits the ambient temperature operating range based on the **T_A range over V_{BAT} and V_{OUT}** chart, Figure 11-8 on page 78. If the temperature range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.
4. Determine if the desired output current (I_{OUT}) range fits the output current operating range based on the **I_{OUT} range over V_{BAT} and V_{OUT}** chart, Figure 11-9 on page 78. If the output current range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.
5. Find the allowed inductor values based on the **L_{BOOST} values over V_{BAT} and V_{OUT}** chart, Figure 11-10 on page 78.
6. Based on the allowed inductor values, inductor dimensions, inductor cost, boost efficiency, and V_{RIPPLE} choose the optimum inductor value for the system. Boost efficiency and V_{RIPPLE} typical values are provided in the **Efficiency vs V_{BAT}** and **V_{RIPPLE} vs V_{BAT}** charts, Figure 11-11 on page 79 through Figure 11-14 on page 79. In general, if high efficiency and low V_{RIPPLE} are most important, then the highest allowed inductor value should be used. If low inductor cost or small inductor size are most important, then one of the smaller allowed inductor values should be used. If the allowed inductor(s) efficiency, V_{RIPPLE}, cost or dimensions are not acceptable for the application than an external boost regulator should be used.

6.3 Reset

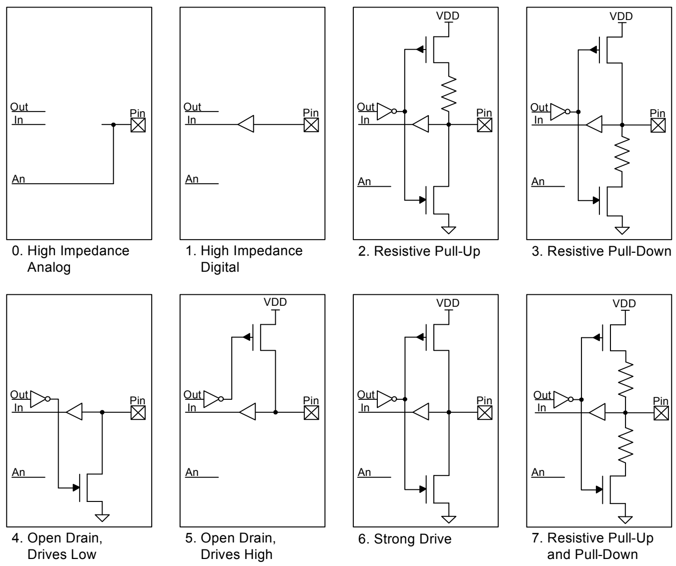
CY8C36 has multiple internal and external reset sources available. The reset sources are:

- Power source monitoring – The analog and digital power voltages, VDDA, VDDD, VCCA, and VCCD are monitored in several different modes during power up, active mode, and sleep mode (buzzing). If any of the voltages goes outside predetermined ranges then a reset is generated. The monitors are programmable to generate an interrupt to the processor under certain conditions before reaching the reset thresholds.
- External – The device can be reset from an external source by pulling the reset pin (XRES) low. The XRES pin includes an internal pull-up to VDDIO1. VDDD, VDDA, and VDDIO1 must all have voltage applied before the part comes out of reset.
- Watchdog timer – A watchdog timer monitors the execution of instructions by the processor. If the watchdog timer is not reset by firmware within a certain period of time, the watchdog timer generates a reset.
- Software – The device can be reset under program control.

6.4.1 Drive Modes

Each GPIO and SIO pin is individually configurable into one of the eight drive modes listed in Table 6-3. Three configuration bits are used for each pin (DM[2:0]) and set in the PRTxDM[2:0] registers. Figure 6-12 depicts a simplified pin view based on each of the eight drive modes. Table 6-3 shows the I/O pin's drive state based on the port data register value or digital array signal if bypass mode is selected. Note that the actual I/O pin voltage is determined by a combination of the selected drive mode and the load at the pin. For example, if a GPIO pin is configured for resistive pull-up mode and driven high while the pin is floating, the voltage measured at the pin is a high logic state. If the same GPIO pin is externally tied to ground then the voltage unmeasured at the pin is a low logic state.

Figure 6-12. Drive Mode



The 'Out' connection is driven from either the Digital System (when the Digital Output terminal is connected) or the Data Register (when HW connection is disabled).
The 'In' connection drives the Pin State register, and the Digital System if the Digital Input terminal is enabled and connected.
The 'An' connection connects to the Analog System.

Table 6-3. Drive Modes

Diagram	Drive Mode	PRTxDM2	PRTxDM1	PRTxDM0	PRTxDR = 1	PRTxDR = 0
0	High impedance analog	0	0	0	High Z	High Z
1	High impedance digital	0	0	1	High Z	High Z
2	Resistive pull-up[18]	0	1	0	Res High (5K)	Strong Low
3	Resistive pull-down[18]	0	1	1	Strong High	Res Low (5K)
4	Open drain, drives low	1	0	0	High Z	Strong Low
5	Open drain, drive high	1	0	1	Strong High	High Z
6	Strong drive	1	1	0	Strong High	Strong Low
7	Resistive pull-up and pull-down[18]	1	1	1	Res High (5K)	Res Low (5K)

Note
18. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

The USBIO pins (P15[7] and P15[6]), when enabled for I/O mode, have limited drive mode control. The drive mode is set using the PRT15.DM0[7, 6] register. A resistive pull option is also available at the USBIO pins, which can be enabled using the PRT15.DM1[7, 6] register. When enabled for USB mode, the drive mode control has no impact on the configuration of the USB pins. Unlike the GPIO and SIO configurations, the port wide configuration registers do not configure the USB drive mode bits. Table 6-4 shows the drive mode configuration for the USBIO pins.

Table 6-4. USBIO Drive Modes (P15[7] and P15[6])

PRT15.DM1[7,6] Pull up enable	PRT15.DM0[7,6] Drive Mode enable	PRT15.DR[7,6] = 1	PRT15.DR[7,6] = 0	Description
0	0	High Z	Strong Low	Open Drain, Strong Low
0	1	Strong High	Strong Low	Strong Outputs
1	0	Res High (5k)	Strong Low	Resistive Pull Up, Strong Low
1	1	Strong High	Strong Low	Strong Outputs

- High Impedance Analog

  The default reset state with both the output driver and digital input buffer turned off. This prevents any current from flowing in the I/O's digital input buffer due to a floating voltage. This state is recommended for pins that are floating or that support an analog voltage. High impedance analog pins do not provide digital input functionality.

  To achieve the lowest chip current in sleep modes, all I/Os must either be configured to the high impedance analog mode, or have their pins driven to a power supply rail by the PSoC device or by external circuitry.

- High Impedance Digital

  The input buffer is enabled for digital signal input. This is the standard high impedance (HiZ) state recommended for digital inputs.

- Resistive pull-up or resistive pull-down

  Resistive pull-up or pull-down, respectively, provides a series resistance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. Interfacing to mechanical switches is a common application for these modes. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

- Open Drain, Drives High and Open Drain, Drives Low

  Open drain modes provide high impedance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. A common application for these modes is driving the I^2C bus signal lines.

- Strong Drive

  Provides a strong CMOS output drive in either high or low state. This is the standard output mode for pins. Strong Drive mode pins must not be used as inputs under normal circumstances. This mode is often used to drive digital output signals or external FETs.

- Resistive pull-up and pull-down

  Similar to the resistive pull-up and resistive pull-down modes except the pin is always in series with a resistor. The high data state is pull-up while the low data state is pull-down. This mode is most often used when other signals that may cause shorts can drive the bus. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

6.4.2 Pin Registers

Registers to configure and interact with pins come in two forms that may be used interchangeably.

All I/O registers are available in the standard port form, where each bit of the register corresponds to one of the port pins. This register form is efficient for quickly reconfiguring multiple port pins at the same time.

I/O registers are also available in pin form, which combines the eight most commonly used port register bits into a single register for each pin. This enables very fast configuration changes to individual pins with a single register write.

6.4.3 Bidirectional Mode

High speed bidirectional capability allows pins to provide both the high impedance digital drive mode for input signals and a second user selected drive mode such as strong drive (set using PRT×DM[2:0] registers) for output signals on the same pin, based on the state of an auxiliary control bus signal. The bidirectional capability is useful for processor busses and communications interfaces such as the SPI Slave MISO pin that requires dynamic hardware control of the output buffer.

The auxiliary control bus routes up to 16 UDB or digital peripheral generated output enable signals to one or more pins.

6.4.4 Slew Rate Limited Mode

GPIO and SIO pins have fast and slow output slew rate options for strong and open drain drive modes, not resistive drive modes. Because it results in reduced EMI, the slow edge rate option is recommended for signals that are not speed critical, generally less than 1 MHz. The fast slew rate is for signals between 1 MHz and 33 MHz. The slew rate is individually configurable for each pin, and is set by the PRT×SLW registers.

6.4.5 Pin Interrupts

All GPIO and SIO pins are able to generate interrupts to the system. All eight pins in each port interface to their own Port Interrupt Control Unit (PICU) and associated interrupt vector. Each pin of the port is independently configurable to detect rising edge, falling edge, both edge interrupts, or to not generate an interrupt.

Depending on the configured mode for each pin, each time an interrupt event occurs on a pin, its corresponding status bit of the interrupt status register is set to “1” and an interrupt request is sent to the interrupt controller. Each PICU has its own interrupt vector in the interrupt controller and the pin status register providing easy determination of the interrupt source down to the pin level.

Port pin interrupts remain active in all sleep modes allowing the PSoC device to wake from an externally generated interrupt.

While level sensitive interrupts are not directly supported; universal digital blocks (UDB) provide this functionality to the system when needed.

6.4.6 Input Buffer Mode

GPIO and SIO input buffers can be configured at the port level for the default CMOS input thresholds or the optional LVTTL input thresholds. All input buffers incorporate Schmitt triggers for input hysteresis. Additionally, individual pin input buffers can be disabled in any drive mode.

6.4.7 I/O Power Supplies

Up to four I/O pin power supplies are provided depending on the device and package. Each I/O supply must be less than or equal to the voltage on the chip’s analog (VDDA) pin. This feature allows users to provide different I/O voltage levels for different pins on the device. Refer to the specific device package pinout to determine VDDIO capability for a given port and pin.

The SIO port pins support an additional regulated high output capability, as described in Adjustable Output Level.

6.4.8 Analog Connections

These connections apply only to GPIO pins. All GPIO pins may be used as analog inputs or outputs. The analog voltage present on the pin must not exceed the VDDIO supply voltage to which the GPIO belongs. Each GPIO may connect to one of the analog global busses or to one of the analog mux buses to connect any pin to any internal analog resource such as ADC or comparators. In addition, select pins provide direct connections to specific analog features such as the high current DACs or uncommitted opamps.

6.4.9 CapSense

This section applies only to GPIO pins. All GPIO pins may be used to create CapSense buttons and sliders[19]. See the “CapSense” section on page 63 for more information.

6.4.10 LCD Segment Drive

This section applies only to GPIO pins. All GPIO pins may be used to generate Segment and Common drive signals for direct glass drive of LCD glass. See the “LCD Direct Drive” section on page 62 for details.

6.4.11 Adjustable Output Level

This section applies only to SIO pins. SIO port pins support the ability to provide a regulated high output level for interface to external signals that are lower in voltage than the SIO’s respective VDDIO. SIO pins are individually configurable to output either the standard VDDIO level or the regulated output, which is based on an internally generated reference. Typically a voltage DAC (VDAC) is used to generate the reference (see Figure 6-13). The “DAC” section on page 64 has more details on VDAC use and reference routing to the SIO pins. Resistive pull-up and pull-down drive modes are not available with SIO in regulated output mode.

6.4.12 Adjustable Input Level

This section applies only to SIO pins. SIO pins by default support the standard CMOS and LVTTL input levels but also support a differential mode with programmable levels. SIO pins are grouped into pairs. Each pair shares a reference generator block which, is used to set the digital input buffer reference level for interface to external signals that differ in voltage from VDDIO. The reference sets the pins voltage threshold for a high logic level (see Figure 6-13). Available input thresholds are:

- $0.5 \times$ VDDIO
- $0.4 \times$ VDDIO
- $0.5 \times V_{REF}$
- V_{REF}

Typically a voltage DAC (VDAC) generates the V_{REF} reference. “DAC” section on page 64 has more details on VDAC use and reference routing to the SIO pins.

Note

19. GPIOs with opamp outputs are not recommended for use with CapSense

6.4.19 JTAG Boundary Scan

The device supports standard JTAG boundary scan chains on all I/O pins for board level test.

7. Digital Subsystem

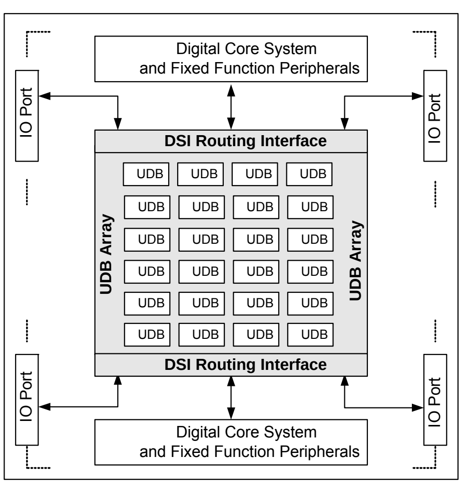
The digital programmable system creates application specific combinations of both standard and advanced digital peripherals and custom logic functions. These peripherals and logic are then interconnected to each other and to any pin on the device, providing a high level of design flexibility and IP security.

The features of the digital programmable system are outlined here to provide an overview of capabilities and architecture. You do not need to interact directly with the programmable digital system at the hardware and register level. PSoC Creator provides a high level schematic capture graphical interface to automatically place and route resources similar to PLDs.

The main components of the digital programmable system are:

- Universal Digital Blocks (UDB) – These form the core functionality of the digital programmable system. UDBs are a collection of uncommitted logic (PLD) and structural logic (Datapath) optimized to create all common embedded peripherals and customized functionality that are application or design specific.
- Universal Digital Block Array – UDB blocks are arrayed within a matrix of programmable interconnect. The UDB array structure is homogeneous and allows for flexible mapping of digital functions onto the array. The array supports extensive and flexible routing interconnects between UDBs and the Digital System Interconnect.
- Digital System Interconnect (DSI) – Digital signals from Universal Digital Blocks (UDBs), fixed function peripherals, I/O pins, interrupts, DMA, and other system core signals are attached to the Digital System Interconnect to implement full featured device connectivity. The DSI allows any digital function to any pin or other feature routability when used with the Universal Digital Block Array.

Figure 7-1. CY8C36 Digital Programmable Architecture



7.1 Example Peripherals

The flexibility of the CY8C36 family's Universal Digital Blocks (UDBs) and Analog Blocks allow the user to create a wide range of components (peripherals). The most common peripherals were built and characterized by Cypress and are shown in the PSoC Creator component catalog, however, users may also create their own custom components using PSoC Creator. Using PSoC Creator, users may also create their own components for reuse within their organization, for example sensor interfaces, proprietary algorithms, and display interfaces.

The number of components available through PSoC Creator is too numerous to list in the data sheet, and the list is always growing. An example of a component available for use in CY8C36 family, but, not explicitly called out in this data sheet is the UART component.

7.1.1 Example Digital Components

The following is a sample of the digital components available in PSoC Creator for the CY8C36 family. The exact amount of hardware resources (UDBs, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- Communications
  - I^2C
  - UART
  - SPI
- Functions
  - EMIF
  - PWMs
  - Timers
  - Counters
- Logic
  - NOT
  - OR
  - XOR
  - AND

7.1.2 Example Analog Components

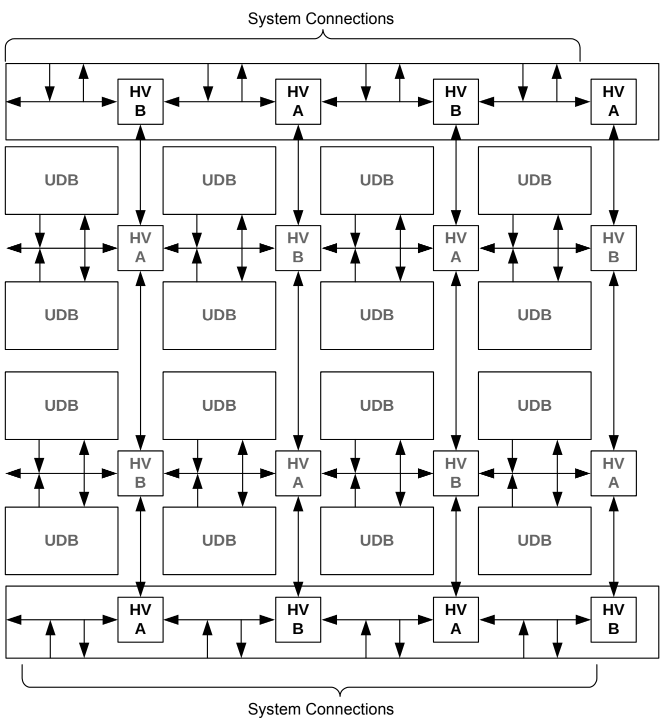
The following is a sample of the analog components available in PSoC Creator for the CY8C36 family. The exact amount of hardware resources (SC/CT blocks, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- Amplifiers
  - TIA
  - PGA
  - opamp
- ADC
  - Delta-Sigma
- DACs
  - Current
  - Voltage
  - PWM
- Comparators
- Mixers

7.3 UDB Array Description

Figure 7-7 shows an example of a 16-UDB array. In addition to the array core, there are a DSI routing interfaces at the top and bottom of the array. Other interfaces that are not explicitly shown include the system interfaces for bus and clock distribution. The UDB array includes multiple horizontal and vertical routing channels each comprised of 96 wires. The wire connections to UDBs, at horizontal/vertical intersection and at the DSI interface are highly permutable providing efficient automatic routing in PSoC Creator. Additionally the routing allows wire by wire segmentation along the vertical and horizontal routing to further increase routing flexibility and capability.

Figure 7-7. Digital System Interface Structure

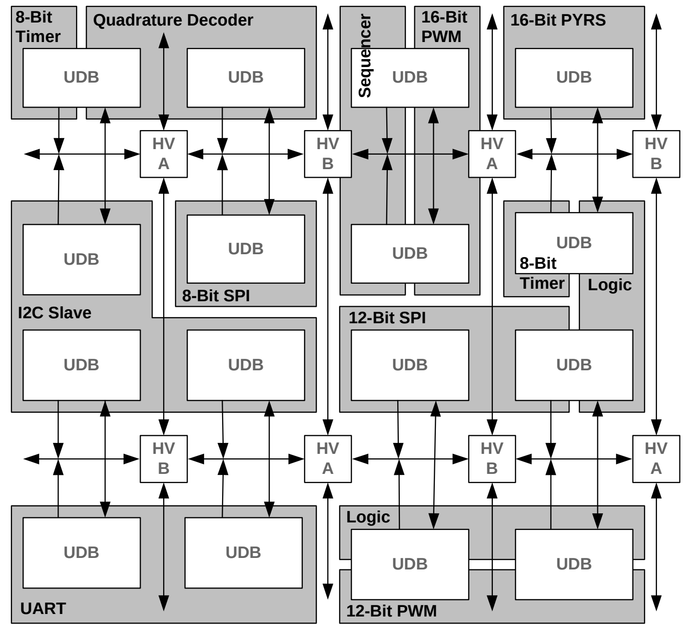


7.3.1 UDB Array Programmable Resources

Figure 7-8 shows an example of how functions are mapped into a bank of 16 UDBs. The primary programmable resources of the UDB are two PLDs, one datapath and one status/control register. These resources are allocated independently, because they have independently selectable clocks, and therefore unused blocks are allocated to other unrelated functions.

An example of this is the 8-bit Timer in the upper left corner of the array. This function only requires one datapath in the UDB, and therefore the PLD resources may be allocated to another function. A function such as a Quadrature Decoder may require more PLD logic than one UDB can supply and in this case can utilize the unused PLD blocks in the 8-bit Timer UDB. Programmable resources in the UDB array are generally homogeneous so functions can be mapped to arbitrary boundaries in the array.

Figure 7-8. Function Mapping Example in a Bank of UDBs



7.4 DSI Routing Interface Description

The DSI routing interface is a continuation of the horizontal and vertical routing channels at the top and bottom of the UDB array core. It provides general purpose programmable routing between device peripherals, including UDBs, I/Os, analog peripherals, interrupts, DMA and fixed function peripherals.

Figure 7-9 illustrates the concept of the digital system interconnect, which connects the UDB array routing matrix with other device peripherals. Any digital core or fixed function peripheral that needs programmable routing is connected to this interface.

Signals in this category include:

- Interrupt requests from all digital peripherals in the system.
- DMA requests from all digital peripherals in the system.
- Digital peripheral data signals that need flexible routing to I/Os.
- Digital peripheral data signals that need connections to UDBs.
- Connections to the interrupt and DMA controllers.
- Connection to I/O pins.
- Connection to analog system digital signals.

7.9 Digital Filter Block

Some devices in the CY8C36 family of devices have a dedicated HW accelerator block used for digital filtering. The DFB has a dedicated multiplier and accumulator that calculates a 24-bit by 24-bit multiply accumulate in one bus clock cycle. This enables the mapping of a direct form FIR filter that approaches a computation rate of one FIR tap for each clock cycle. The MCU can implement any of the functions performed by this block, but at a slower rate that consumes MCU bandwidth.

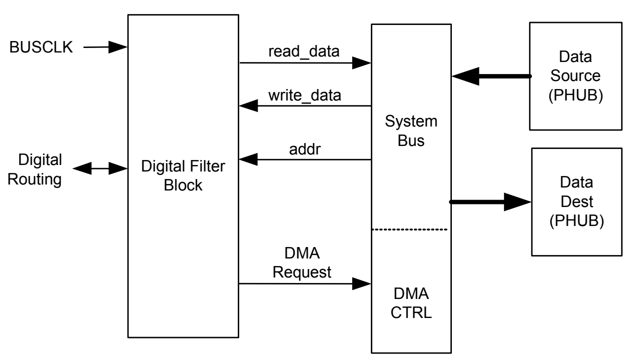
The heart of the DFB is a datapath (DP), which is the numerical calculation unit of the DFB. The DP is a 24-bit fixed-point numerical processor containing a 48-bit multiply and accumulate function (MAC), a multi-function ALU, sample and coefficient data RAMs as well as data routing, shifting, holding and rounding functions.

In the MAC, two 24-bit values can be multiplied and the result added to the 48-bit accumulator in each bus clock cycle. The MAC is the only portion of the DP that is wider than 24 bits. All results from the MAC are passed on to the ALU as 24-bit values representing the high-order 24 bits in the accumulator shifted by one (bits 46:23). The MAC assumes an implied binary point after the most significant bit.

The DP also contains an optimized ALU that supports add, subtract, comparison, threshold, absolute value, squelch, saturation, and other functions. The DP unit is controlled by seven control fields totaling 18 bits coming from the DFB Controller. For more information see the TRM.

The PSoC Creator interface provides a wizard to implement FIR and IIR digital filters with coefficients for LPF, BPF, HPF, Notch and arbitrary shape filters. 64 pairs of data and coefficients are stored. This enables a 64 tap FIR filter or up to 4 16 tap filters of either FIR or IIR formulation.

Figure 7-20. DFB Application Diagram (pwr/gnd not shown)



The typical use model is for data to be supplied to the DFB over the system bus from another on-chip system data source such as an ADC. The data typically passes through main memory or is directly transferred from another chip resource through DMA. The DFB processes this data and passes the result to another on chip resource such as a DAC or main memory through DMA on the system bus.

Data movement in or out of the DFB is typically controlled by the system DMA controller but can be moved directly by the MCU.

8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

- Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses.
- High resolution Delta-Sigma ADC.
- Up to four 8-bit DACs that provide either voltage or current output.
- Four comparators with optional connection to configurable LUT outputs.
- Up to four configurable switched capacitor/continuous time (SC/CT) blocks for functions that include opamp, unity gain buffer, programmable gain amplifier, transimpedance amplifier, and mixer.
- Up to four opamps for internal use and connection to GPIO that can be used as high current output buffers.
- CapSense subsystem to enable capacitive touch sensing.
- Precision reference for generating an accurate analog voltage for internal analog blocks.

The same opamps and block interfaces are also connectable to an array of resistors which allows the construction of a variety of continuous time functions.

The opamp and resistor array is programmable to perform various analog functions including

- Naked operational amplifier – Continuous mode
- Unity-gain buffer – Continuous mode
- Programmable gain amplifier (PGA) – Continuous mode
- Transimpedance amplifier (TIA) – Continuous mode
- Up/down mixer – Continuous mode
- Sample and hold mixer (NRZ S/H) – Switched cap mode
- First order analog to digital modulator – Switched cap mode

8.5.1 Naked Opamp

The Naked Opamp presents both inputs and the output for connection to internal or external signals. The opamp has a unity gain bandwidth greater than 6.0 MHz and output drive current up to 650 µA. This is sufficient for buffering internal signals (such as DAC outputs) and driving external loads greater than 7.5 kΩ.

8.5.2 Unity Gain

The Unity Gain buffer is a Naked Opamp with the output directly connected to the inverting input for a gain of 1.00. It has a –3 dB bandwidth greater than 6.0 MHz.

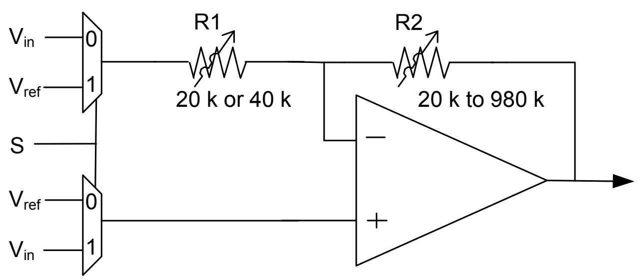
8.5.3 PGA

The PGA amplifies an external or internal signal. The PGA can be configured to operate in inverting mode or noninverting mode. The PGA function may be configured for both positive and negative gains as high as 50 and 49 respectively. The gain is adjusted by changing the values of R1 and R2 as illustrated in Figure 8-8 on page 62. The schematic in Figure 8-8 on page 62 shows the configuration and possible resistor settings for the PGA. The gain is switched from inverting and non inverting by changing the shared select value of the both the input muxes. The bandwidth for each gain case is listed in Table 8-3.

Table 8-3. Bandwidth

Gain	Bandwidth
1	6.0 MHz
24	340 kHz
48	220 kHz
50	215 kHz

Figure 8-8. PGA Resistor Settings



The PGA is used in applications where the input signal may not be large enough to achieve the desired resolution in the ADC, or dynamic range of another SC/CT block such as a mixer. The gain is adjustable at runtime, including changing the gain of the PGA prior to each ADC sample.

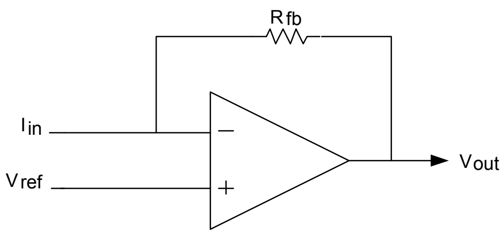
8.5.4 TIA

The Transimpedance Amplifier (TIA) converts an internal or external current to an output voltage. The TIA uses an internal feedback resistor in a continuous time configuration to convert input current to output voltage. For an input current I_{in}, the output voltage is $V_{REF} - I_{in} \times R_{fb}$, where V_{REF} is the value placed on the non inverting input. The feedback resistor Rfb is programmable between 20 KΩ and 1 MΩ through a configuration register. Table 8-4 shows the possible values of Rfb and associated configuration settings.

Table 8-4. Feedback Resistor Settings

Configuration Word	Nominal R_{fb} (KΩ)
000b	20
001b	30
010b	40
011b	60
100b	120
101b	250
110b	500
111b	1000

Figure 8-9. Continuous Time TIA Schematic



The TIA configuration is used for applications where an external sensor's output is current as a function of some type of stimulus such as temperature, light, magnetic flux etc. In a common application, the voltage DAC output can be connected to the V_{REF} TIA input to allow calibration of the external sensor bias current by adjusting the voltage DAC output voltage.

8.6 LCD Direct Drive

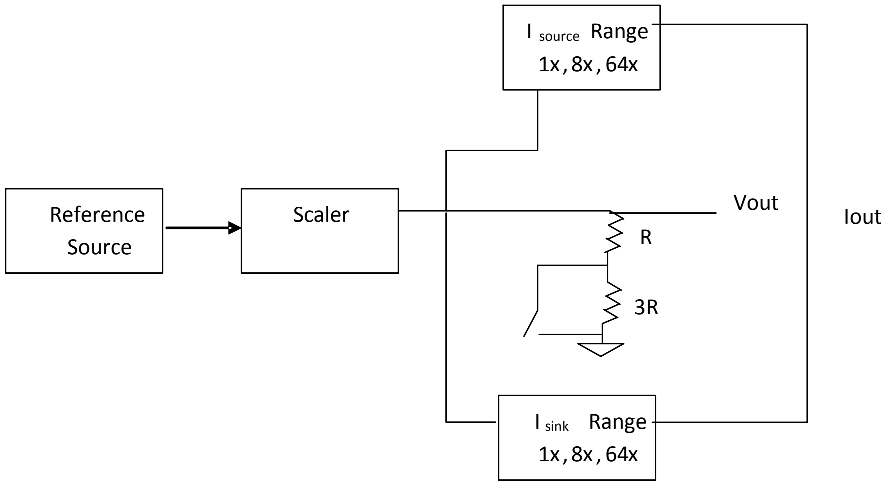
The PSoC Liquid Crystal Display (LCD) driver system is a highly configurable peripheral designed to allow PSoC to directly drive a broad range of LCD glass. All voltages are generated on chip, eliminating the need for external components. With a high multiplex ratio of up to 1/16, the CY8C36 family LCD driver system can drive a maximum of 736 segments. The PSoC LCD driver module was also designed with the conservative power budget of portable devices in mind, enabling different LCD drive modes and power down modes to conserve power.

8.9 DAC

The CY8C36 parts contain up to four Digital to Analog Convertors (DACs). Each DAC is 8-bit and can be configured for either voltage or current output. The DACs support CapSense, power supply regulation, and waveform generation. Each DAC has the following features:

- Adjustable voltage or current output in 255 steps
- Programmable step size (range selection)
- Eight bits of calibration to correct ± 25% of gain error
- Source and sink option for current output
- High and low speed / power modes
- 8 Msps conversion rate for current output
- 1 Msps conversion rate for voltage output
- Monotonic in nature
- Data and strobe inputs can be provided by the CPU or DMA, or routed directly from the DSI
- Dedicated low-resistance output pin for high-current mode

Figure 8-11. DAC Block Diagram



8.9.1 Current DAC

The current DAC (IDAC) can be configured for the ranges 0 to 31.875 µA, 0 to 255 µA, and 0 to 2.04 mA. The IDAC can be configured to source or sink current.

8.9.2 Voltage DAC

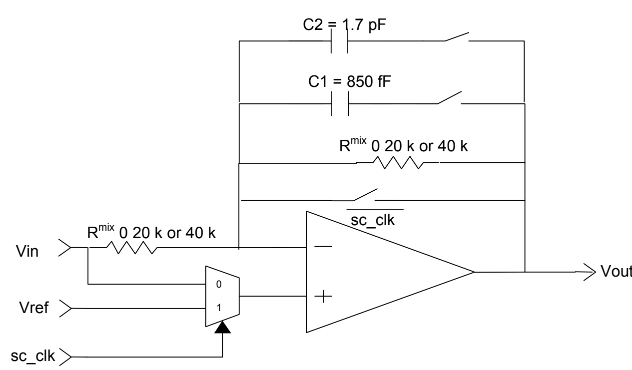
For the voltage DAC (VDAC), the current DAC output is routed through resistors. The two ranges available for the VDAC are 0 to 1.02 V and 0 to 4.08 V. In voltage mode any load connected to the output of a DAC should be purely capacitive (the output of the VDAC is not buffered).

8.10 Up/Down Mixer

In continuous time mode, the SC/CT block components are used to build an up or down mixer. Any mixing application contains an input signal frequency and a local oscillator frequency. The polarity of the clock, Fclk, switches the amplifier between inverting or noninverting gain. The output is the product of the input and the switching function from the local oscillator, with frequency components at the local oscillator plus and minus the signal frequency (Fclk + Fin and Fclk – Fin) and reduced-level frequency components at odd integer multiples of the local oscillator frequency. The local oscillator frequency is provided by the selected clock source for the mixer.

Continuous time up and down mixing works for applications with input signals and local oscillator frequencies up to 1 MHz.

Figure 8-12. Mixer Configuration



9.2 Serial Wire Debug Interface

The SWD interface is the preferred alternative to the JTAG interface. It requires only two pins instead of the four or five needed by JTAG. SWD provides all of the programming and debugging features of JTAG at the same speed. SWD does not provide access to scan chains or device chaining. The SWD clock frequency can be up to 1/3 of the CPU clock frequency.

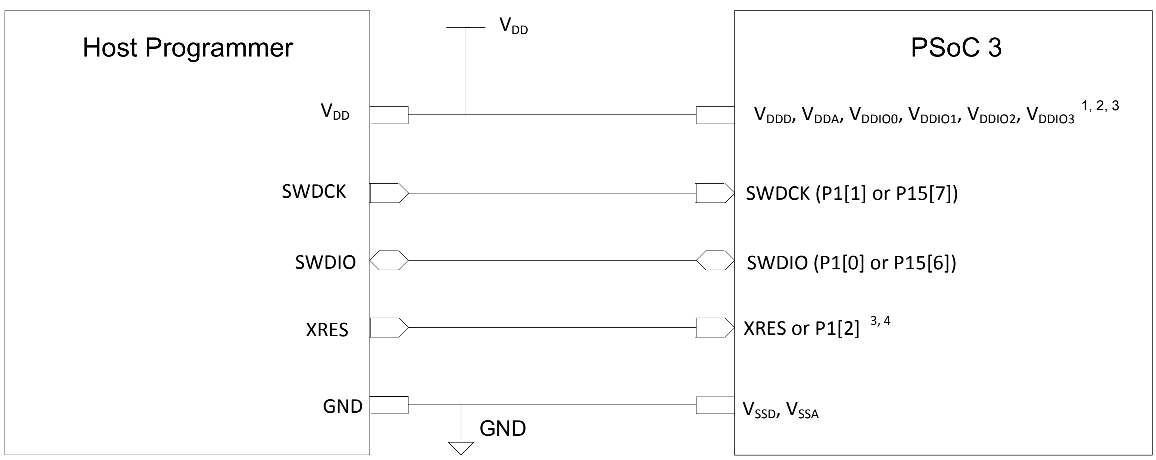
SWD uses two pins, either two of the JTAG pins (TMS and TCK) or the USBIO D+ and D– pins. The USBIO pins are useful for in system programming of USB solutions that would otherwise require a separate programming connector. One pin is used for the data clock and the other is used for data input and output.

SWD can be enabled on only one of the pin pairs at a time. This only happens if, within 8 µs (key window) after reset, that pin pair (JTAG or USB) receives a predetermined acquire sequence of 1s and 0s. If the NVL latches are set for SWD (see *Section 5.5*), this sequence need not be applied to the JTAG pin pair. The acquire sequence must always be applied to the USB pin pair.

SWD is used for debugging or for programming the flash memory.

The SWD interface can be enabled from the JTAG interface or disabled, allowing its pins to be used as GPIO. Unlike JTAG, the SWD interface can always be reacquired on any device during the key window. It can then be used to reenable the JTAG interface, if desired. When using SWD or JTAG pins as standard GPIO, make sure that the GPIO functionality and PCB circuits do not interfere with SWD or JTAG use.

Figure 9-2. SWD Interface Connections between PSoC 3 and Programmer



[1] The voltage levels of the Host Programmer and the PSoC 3 voltage domains involved in Programming should be the same. XRES pin (XRES_N or P1[2]) is powered by V_{DDIO1}. The USB SWD pins are powered by V_{DDD}. So for Programming using the USB SWD pins with XRES pin, the V_{DDD}, V_{DDIO1} of PSoC 3 should be at the same voltage level as Host V_{DD}. Rest of PSoC 3 voltage domains (V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer. The Port 1 SWD pins are powered by V_{DDIO1}. So V_{DDIO1} of PSoC 3 should be at same voltage level as host V_{DD} for Port 1 SWD programming. Rest of PSoC 3 voltage domains (V_{DDD}, V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer.

[2] Vdda must be greater than or equal to all other power supplies (Vddd, Vddio’s) in PSoC 3.

[3] For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio’s) to PSoC 3. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.

[4] P1[2] will be configured as XRES by default only for 48-pin devices (without dedicated XRES pin). For devices with dedicated XRES pin, P1[2] is GPIO pin by default. So use P1[2] as Reset pin only for 48-pin devices, but use dedicated XRES pin for rest of devices.

Table 11-2. DC Specifications *(continued)*

Parameter	Description	Conditions		Min	Typ[29]	Max	Units
	Sleep Mode[32]						
	CPU = OFF RTC = ON (= ECO32K ON, in low-power mode) Sleep timer = ON (= ILO ON at 1 kHz)[33] WDT = OFF I^2C Wake = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 4.5 V - 5.5 V	T = –40 °C	–	1.1	2.3	µA
			T = 25 °C	–	1.1	2.2	
			T = 85 °C	–	15	30	
		$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V	T = –40 °C	–	1	2.2	
			T = 25 °C	–	1	2.1	
			T = 85 °C	–	12	28	
		$V_{DD} = V_{DDIO}$ = 1.71 V – 1.95 V[34]	T = 25 °C	–	2.2	4.2	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF I^2C Wake = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V[35]	T = 25 °C	–	2.2	2.7	
	I^2C Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V[35]	T = 25 °C	–	2.2	2.8	
	Hibernate Mode[32]						
	Hibernate mode current All regulators and oscillators off SRAM retention GPIO interrupts are active Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 4.5 V - 5.5 V	T = –40 °C	–	0.2	1.5	µA
			T = 25 °C	–	0.5	1.5	
			T = 85 °C	–	4.1	5.3	
		$V_{DD} = V_{DDIO}$ = 2.7 V – 3.6 V	T = –40 °C	–	0.2	1.5	
			T = 25 °C	–	0.2	1.5	
			T = 85 °C	–	3.2	4.2	
		$V_{DD} = V_{DDIO}$ = 1.71 V – 1.95 V[34]	T = –40 °C	–	0.2	1.5	
			T = 25 °C	–	0.3	1.5	
			T = 85 °C	–	3.3	4.3	
I_{DDAR}	Analog current consumption while device is reset[36]	$V_{DDA} \leq 3.6$ V		–	0.3	0.6	mA
		$V_{DDA} > 3.6$ V		–	1.4	3.3	mA
I_{DDDR}	Digital current consumption while device is reset[36]	$V_{DDD} \leq 3.6$ V		–	1.1	3.1	mA
		$V_{DDD} > 3.6$ V		–	0.7	3.1	mA

Notes

32. If V_{CCD} and V_{CCA} are externally regulated, the voltage difference between V_{CCD} and V_{CCA} must be less than 50 mV.
33. Sleep timer generates periodic interrupts to wake up the CPU. This specification applies only to those times that the CPU is off.
34. Externally regulated mode.
35. Based on device characterization (not production tested).
36. Based on device characterization (not production tested). USBIO pins tied to ground (VSSD).

Figure 11-1. Active Mode Current vs F_{CPU}, V_{DD} = 3.3 V, Temperature = 25 °C

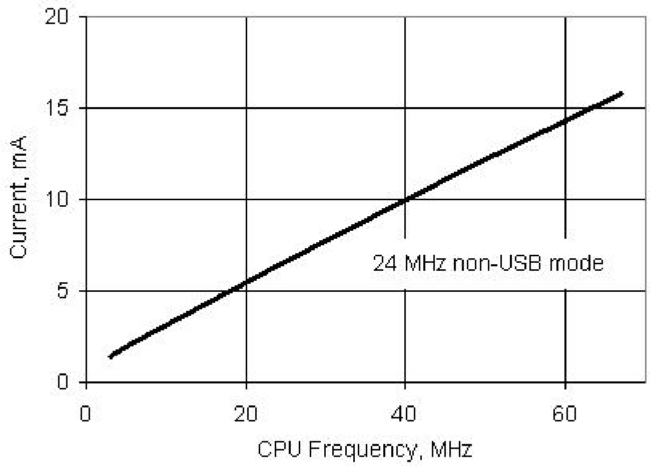


Figure 11-2. Active Mode Current vs Temperature and F_{CPU}, V_{DD} = 3.3 V

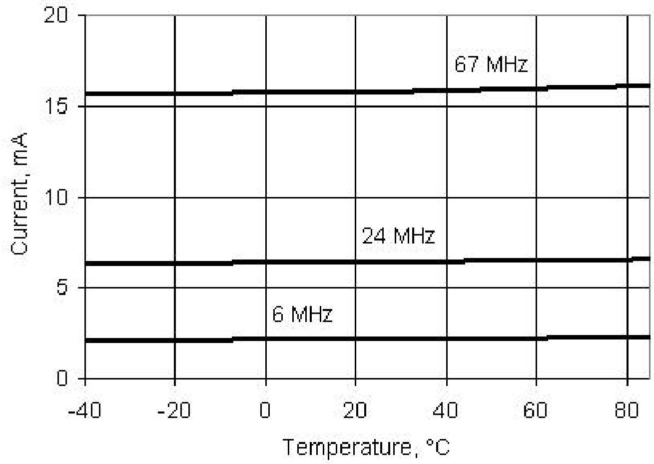


Figure 11-3. Active Mode Current vs V_{DD} and Temperature, F_{CPU} = 24 MHz

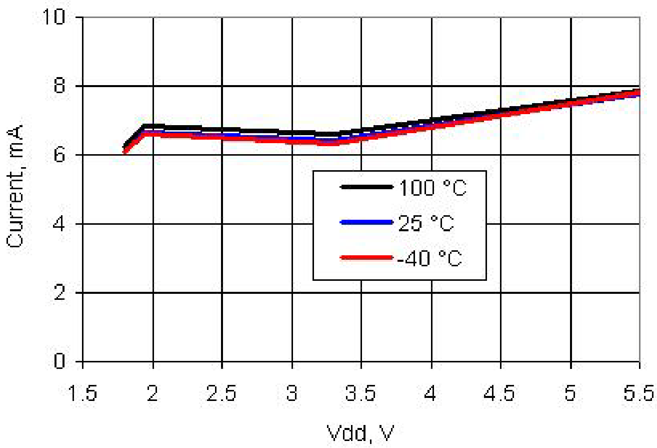


Figure 11-15. GPIO Output High Voltage and Current

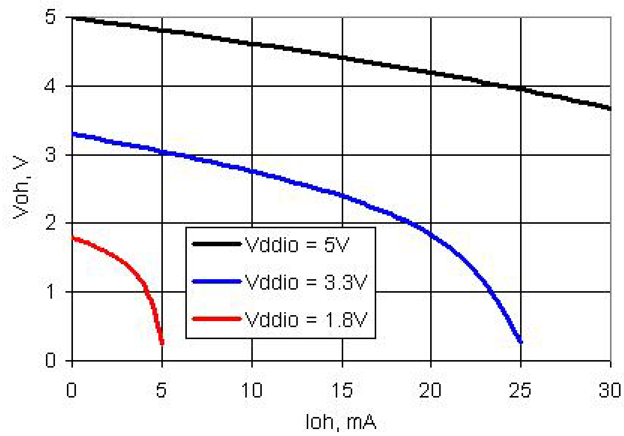


Figure 11-16. GPIO Output Low Voltage and Current

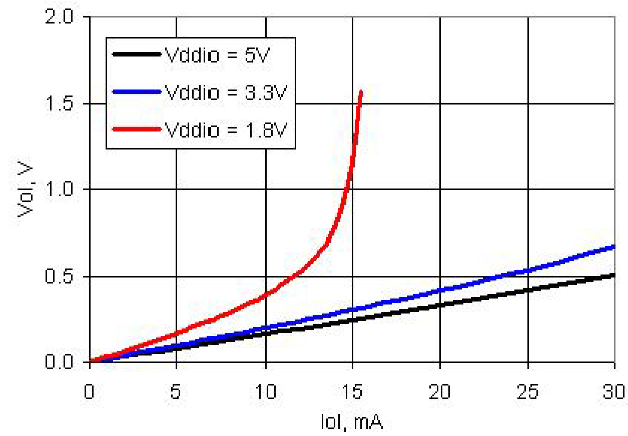


Table 11-10. GPIO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
TriseF	Rise time in Fast Strong Mode[45]	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TfallF	Fall time in Fast Strong Mode[45]	3.3 V V_{DDIO} Cload = 25 pF	–	–	6	ns
TriseS	Rise time in Slow Strong Mode[45]	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
TfallS	Fall time in Slow Strong Mode[45]	3.3 V V_{DDIO} Cload = 25 pF	–	–	60	ns
Fgpioout	GPIO output operating frequency		–	–	–	–
	2.7 V ≤ V_{DDIO} ≤ 5.5 V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	33	MHz
	1.71 V ≤ V_{DDIO} < 2.7 V, fast strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	20	MHz
	3.3 V ≤ V_{DDIO} ≤ 5.5 V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	7	MHz
	1.71 V ≤ V_{DDIO} < 3.3 V, slow strong drive mode	90/10% V_{DDIO} into 25 pF	–	–	3.5	MHz
Fgpioin	GPIO input operating frequency					
	1.71 V ≤ V_{DDIO} ≤ 5.5 V	90/10% V_{DDIO}	–	–	33	MHz

Note
45. Based on device characterization (Not production tested).

Figure 11-46. IDAC Step Response, Codes 0x40 - 0xC0, 255 µA Mode, Source Mode, High speed mode, V_{DDA} = 5 V

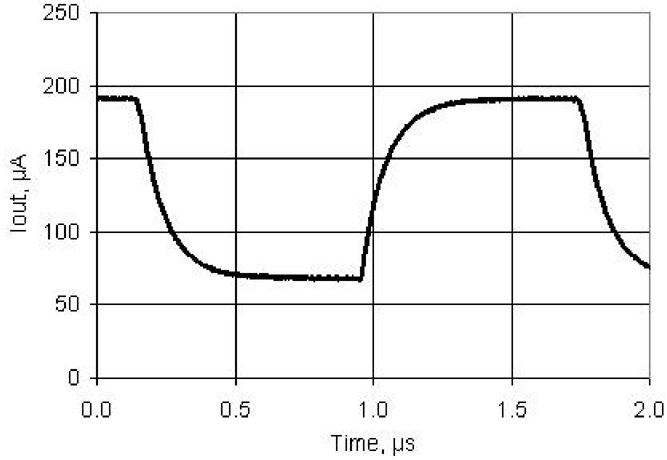


Figure 11-47. IDAC Glitch Response, Codes 0x7F - 0x80, 255 µA Mode, Source Mode, High speed mode, V_{DDA} = 5 V

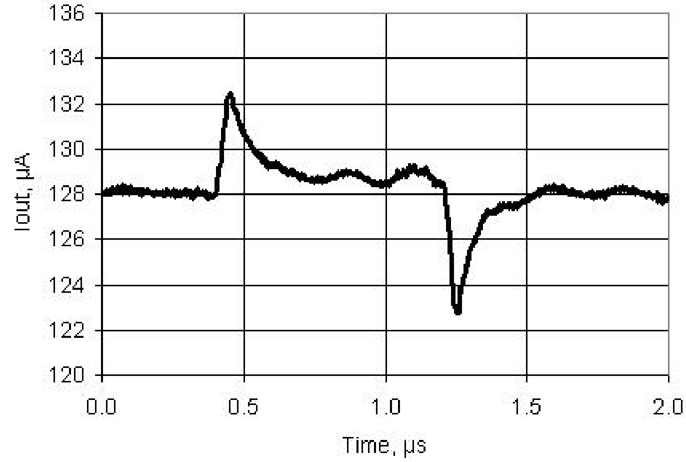


Figure 11-48. IDAC PSRR vs Frequency

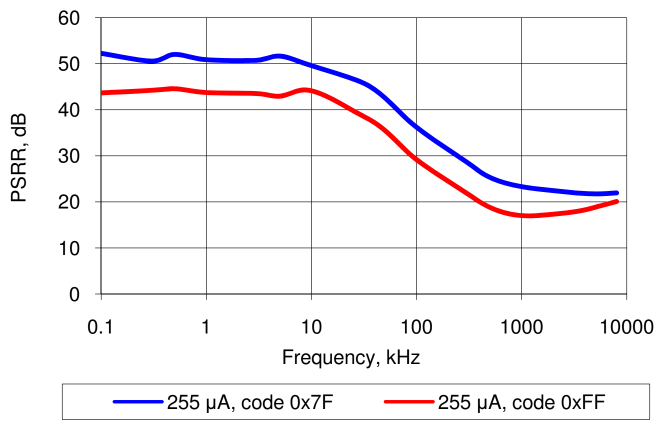


Figure 11-49. IDAC Current Noise, 255 µA Mode, Source Mode, High speed mode, V_{DDA} = 5 V

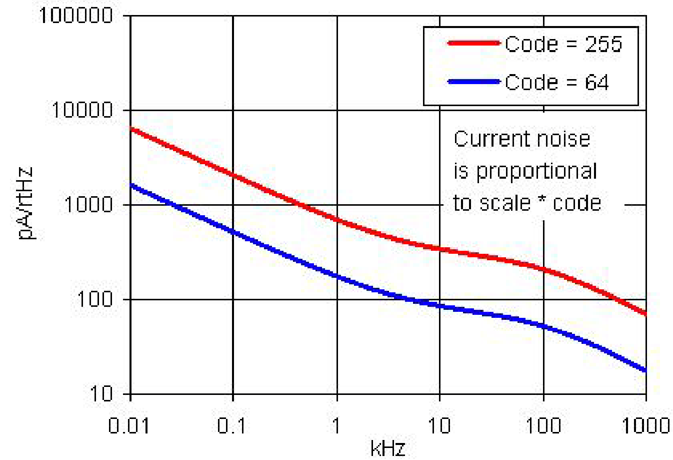


Table 11-31. VDAC AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DAC}	Update rate	1 V scale	–	–	1000	ksps
		4 V scale	–	–	250	ksps
TsettleP	Settling time to 0.1%, step 25% to 75%	1 V scale, Cload = 15 pF	–	0.45	1	µs
		4 V scale, Cload = 15 pF	–	0.8	3.2	µs
TsettleN	Settling time to 0.1%, step 75% to 25%	1 V scale, Cload = 15 pF	–	0.45	1	µs
		4 V scale, Cload = 15 pF	–	0.7	3	µs
	Voltage noise	Range = 1 V, High speed mode, V_{DDA} = 5 V, 10 kHz	–	750	–	nV/sqrtHz

Figure 11-58. VDAC Step Response, Codes 0x40 - 0xC0, 1 V Mode, High speed mode, V_{DDA} = 5 V

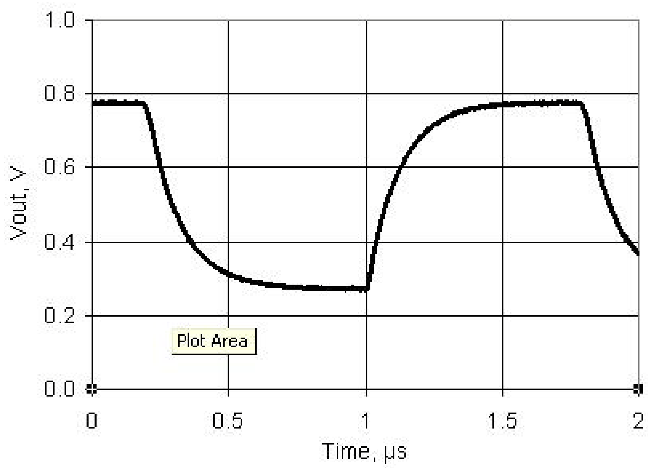


Figure 11-59. VDAC Glitch Response, Codes 0x7F - 0x80, 1 V Mode, High speed mode, V_{DDA} = 5 V

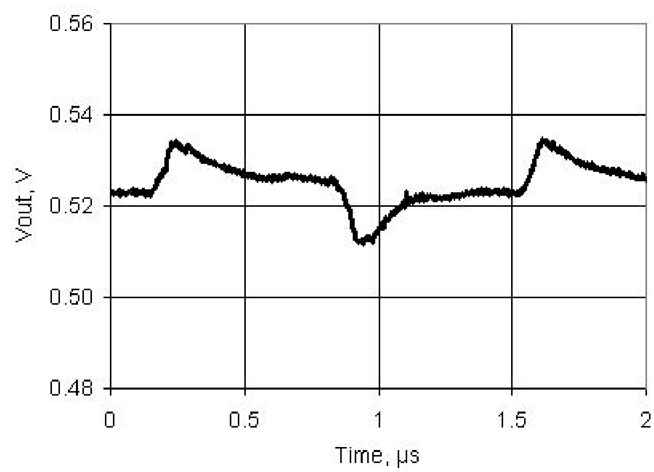


Figure 11-60. VDAC PSRR vs Frequency

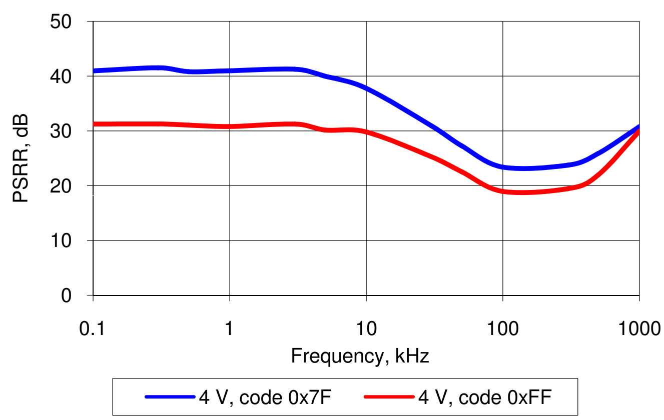
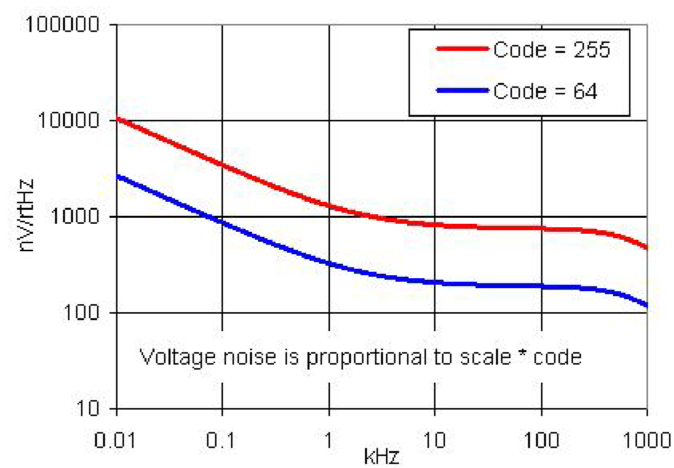


Figure 11-61. VDAC Voltage Noise, 1 V Mode, High speed mode, V_{DDA} = 5 V



11.5.8 Mixer

The mixer is created using a SC/CT analog block; see the Mixer component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-32. Mixer DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{OS}	Input offset voltage		–	–	15	mV
	Quiescent current		–	0.9	2	mA
G	Gain		–	0	–	dB

Table 11-33. Mixer AC Specifications[63]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_{LO}	Local oscillator frequency	Down mixer mode	–	–	4	MHz
f_{in}	Input signal frequency	Down mixer mode	–	–	14	MHz
f_{LO}	Local oscillator frequency	Up mixer mode	–	–	1	MHz
f_{in}	Input signal frequency	Up mixer mode	–	–	1	MHz
SR	Slew rate		3	–	–	V/µs

11.5.9 Transimpedance Amplifier

The TIA is created using a SC/CT analog block; see the TIA component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-34. Transimpedance Amplifier (TIA) DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{IOFF}	Input offset voltage		–	–	10	mV
Rconv	Conversion resistance[64]	R = 20K; 40 pF load	–25	–	+35	%
		R = 30K; 40 pF load	–25	–	+35	%
		R = 40K; 40 pF load	–25	–	+35	%
		R = 80K; 40 pF load	–25	–	+35	%
		R = 120K; 40 pF load	–25	–	+35	%
		R = 250K; 40 pF load	–25	–	+35	%
		R= 500K; 40 pF load	–25	–	+35	%
		R = 1M; 40 pF load	–25	–	+35	%
	Quiescent current		–	1.1	2	mA

Table 11-35. Transimpedance Amplifier (TIA) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
BW	Input bandwidth (–3 dB)	R = 20K; –40 pF load	1500	–	–	kHz
		R = 120K; –40 pF load	240	–	–	kHz
		R = 1M; –40 pF load	25	–	–	kHz

Notes
63. Based on device characterization (Not production tested).
64. Conversion resistance values are not calibrated. Calibrated values and details about calibration are provided in PSoC Creator component data sheets. External precision resistors can also be used.

11.6.6 Digital Filter Block

Table 11-51. DFB DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	DFB operating current	64-tap FIR at F_{DFB}				
		500 kHz (6.7 ksps)	–	0.16	0.27	mA
		1 MHz (13.4 ksps)	–	0.33	0.53	mA
		10 MHz (134 ksps)	–	3.3	5.3	mA
		48 MHz (644 ksps)	–	15.7	25.5	mA
		67 MHz (900 ksps)	–	21.8	35.6	mA

Table 11-52. DFB AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DFB}	DFB operating frequency		DC	–	67.01	MHz

11.6.7 USB

Table 11-53. USB DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{USB_5}	Device supply (V_{DDD}) for USB operation	USB configured, USB regulator enabled	4.35	–	5.25	V
$V_{USB\_3.3}$		USB configured, USB regulator bypassed	3.15	–	3.6	V
V_{USB_3}		USB configured, USB regulator bypassed[66]	2.85	–	3.6	V
$I_{USB\_Configured}$	Device supply current in device active mode, bus clock and IMO = 24 MHz	V_{DDD} = 5 V, F_{CPU} = 1.5 MHz	–	10	–	mA
		V_{DDD} = 3.3 V, F_{CPU} = 1.5 MHz	–	8	–	mA
$I_{USB\_Suspended}$	Device supply current in device sleep mode	V_{DDD} = 5 V, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		V_{DDD} = 5 V, disconnected from USB host	–	0.3	–	mA
		V_{DDD} = 3.3 V, connected to USB host, PICU configured to wake on USB resume signal	–	0.5	–	mA
		V_{DDD} = 3.3 V, disconnected from USB host	–	0.3	–	mA

Note

66. Rise/fall time matching (TR) not guaranteed, see USB Driver AC Specifications on page 87.

Table 11-74. IMO AC Specifications *(continued)*

Parameter	Description	Conditions	Min	Typ	Max	Units
Jp–p	Jitter (peak to peak)[81]					
	F = 24 MHz		–	0.9	–	ns
	F = 3 MHz		–	1.6	–	ns
Jperiod	Jitter (long term)[81]					
	F = 24 MHz		–	0.9	–	ns
	F = 3 MHz		–	12	–	ns

Figure 11-71. IMO Frequency Variation vs. Temperature

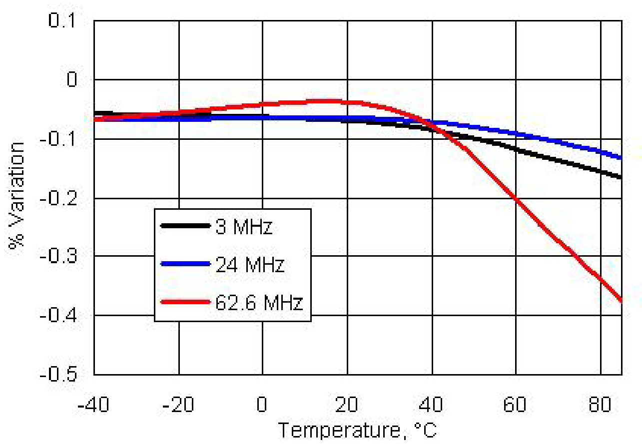
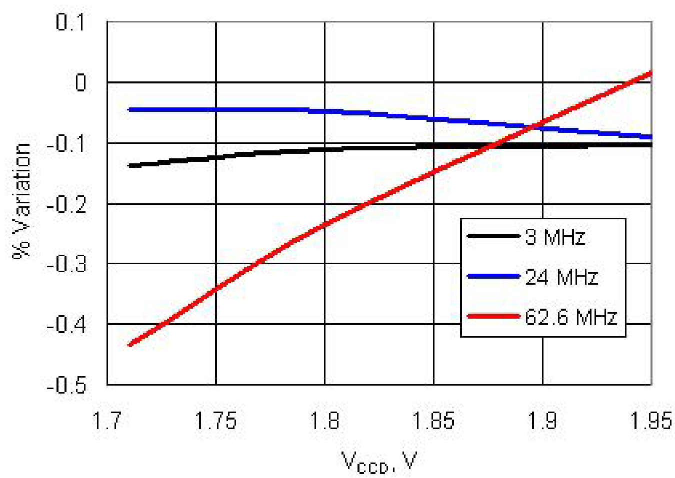


Figure 11-72. IMO Frequency Variation vs. V_{CC}



Note

81. Based on device characterization (Not production tested).

14. Acronyms

Table 14-1. Acronyms Used in this Document

Acronym	Description
abus	analog local bus
ADC	analog-to-digital converter
AG	analog global
AHB	AMBA (advanced microcontroller bus architecture) high-performance bus, an ARM data transfer bus
ALU	arithmetic logic unit
AMUXBUS	analog multiplexer bus
API	application programming interface
APSR	application program status register
ARM®	advanced RISC machine, a CPU architecture
ATM	automatic thump mode
BW	bandwidth
CAN	Controller Area Network, a communications protocol
CMRR	common-mode rejection ratio
CPU	central processing unit
CRC	cyclic redundancy check, an error-checking protocol
DAC	digital-to-analog converter, see also IDAC, VDAC
DFB	digital filter block
DIO	digital input/output, GPIO with only digital capabilities, no analog. See GPIO.
DMA	direct memory access, see also TD
DNL	differential nonlinearity, see also INL
DNU	do not use
DR	port write data registers
DSI	digital system interconnect
DWT	data watchpoint and trace
ECC	error correcting code
ECO	external crystal oscillator
EEPROM	electrically erasable programmable read-only memory
EMI	electromagnetic interference
EMIF	external memory interface
EOC	end of conversion
EOF	end of frame
EPSR	execution program status register
ESD	electrostatic discharge
ETM	embedded trace macrocell
FIR	finite impulse response, see also IIR
FPB	flash patch and breakpoint
FS	full-speed
GPIO	general-purpose input/output, applies to a PSoC pin
HVI	high-voltage interrupt, see also LVI, LVD
IC	integrated circuit
IDAC	current DAC, see also DAC, VDAC
IDE	integrated development environment
I^2C, or IIC	Inter-Integrated Circuit, a communications protocol
IIR	infinite impulse response, see also FIR
ILO	internal low-speed oscillator, see also IMO
IMO	internal main oscillator, see also ILO
INL	integral nonlinearity, see also DNL
I/O	input/output, see also GPIO, DIO, SIO, USBIO
IPOR	initial power-on reset
IPSR	interrupt program status register
IRQ	interrupt request
ITM	instrumentation trace macrocell
LCD	liquid crystal display
LIN	Local Interconnect Network, a communications protocol.
LR	link register
LUT	lookup table
LVD	low-voltage detect, see also LVI
LVI	low-voltage interrupt, see also HVI
LVTTL	low-voltage transistor-transistor logic
MAC	multiply-accumulate
MCU	microcontroller unit
MISO	master-in slave-out
NC	no connect
NMI	nonmaskable interrupt
NRZ	non-return-to-zero
NVIC	nested vectored interrupt controller
NVL	nonvolatile latch, see also WOL
opamp	operational amplifier
PAL	programmable array logic, see also PLD
PC	program counter
PCB	printed circuit board
PGA	programmable gain amplifier

Description Title: PSoC® 3: CY8C36 Family Datasheet Programmable System-on-Chip (PSoC®) *(continued)* Document Number: 001-53413				
Revision	**ECN**	**Submission Date**	**Orig. of Change**	**Description of Change**
*N	3645908	06/14/2012	MKEA	Added paragraph clarifying that to achieve low hibernate current, you must limit the frequency of IO input signals. Revised description of IPOR and clarified PRES term. Changed footnote to state that all GPIO input voltages - not just analog voltages - must be less than Vddio. Updated 100-TQFP package drawing Clarified description of opamp Iout spec Changed “compliant with I2C” to “compatible with I2C” Updated 48-QFN package drawing Changed reset status register description text to clarify that not all reset sources are in the register Updated example PCB layout figure Removed text stating that FTW is a wakeup source Changed supply ramp rate spec from 1 V/ns to 0.066 V/µs Added “based on char” footnote to voltage monitors response time spec Changed analog global spec descriptions and values Added spec for ESD_{HBM} for when Vssa and Vssd are separate Added a statement about support for JTAG programmers and file formats Changed comparator specs and conditions Added text describing flash cache, and updated related text Changed text and added figures describing Vddio source and sink Added a statement about support for JTAG programmers and file formats. Changed comparator specs and conditions Added text on adjustability of buzz frequency Updated terminology for “master” and “system” clock Deleted the text “debug operations are possible while the device is reset” Deleted and updated text regarding SIO performance under certain power ramp conditions Removed from boost mention of 22 µH inductors. This included deleting some graph figures. Changed DAC high and low speed/power mode descriptions and conditions Changed IMO startup time spec Added text on XRES and PRES re-arm times Added text about usage in externally regulated mode Updated package diagram spec 001-45616 to *D revision. Changed supply ramp rate spec from 1 V/ns to 0.066 V/µs Changed text describing SIO modes for overvoltage tolerance Added chip Idd specs for active and low-power modes, for multiple voltage, temperature and usage conditions Added chip Idd specs for active and low-power modes, for multiple voltage, temperature and usage conditions Updated Vref temperature drift specs. Added Vref graphs and footnote. Updated DFB description text Changed load cap conditions in opamp specs Updated del-sig ADC spec tables, to replace three the instances of “16 bit” with “12 bit” Updated package diagram spec 001-45616 to *D revision
*O	3648803	06/18/2012	WKA/ MKEA	No changes. EROS update.